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[54] **GRAPHICAL DATA BASE EDITOR**

[75] Inventors: **Chris M. Pieper**, Hillsboro; **Cathie J. B. Wier**, Portland; **Eric M. Bush; Thomas W. Rudwick, III**, both of Beaverton; **William A. Greenseth**, Portland; **Robert R. Klingenberg; David Du Pont**, both of Beaverton, all of Oreg.

[73] Assignee: **Credence Systems Corporation**, Fremont, Calif.

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Primary Examiner—Phu K. Nguyen
Attorney, Agent, or Firm—Smith-Hill and Bedell

[57] **ABSTRACT**

A system manipulates stimulus/response signal data associated with an integrated circuit design, such as from a computer-aided engineering simulator, and converts the data into a format acceptable by a tester device which tests a prototype or production integrated circuit. The data is graphically displayed as a waveform and as a vector sequence. On-screen editing of either display is reflected in the other display. Further, the same displays are used to convert the data from event-based data into cycle-based template data compatible with a tester. A mix between event and state data during the conversion is allowed. A standard frame generation language is presented for defining tester frames for each signal within a template or timeset. A workbench editor provides for icon-based control of the system.

9 Claims, 68 Drawing Sheets